

Figure 1. Data acquired with Ecopia AHT55T5 Hall effect measuring system for a magnetron sputtered Si-doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> grown at ECSU on Insulating Fe-doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> substrates from two different vendors.

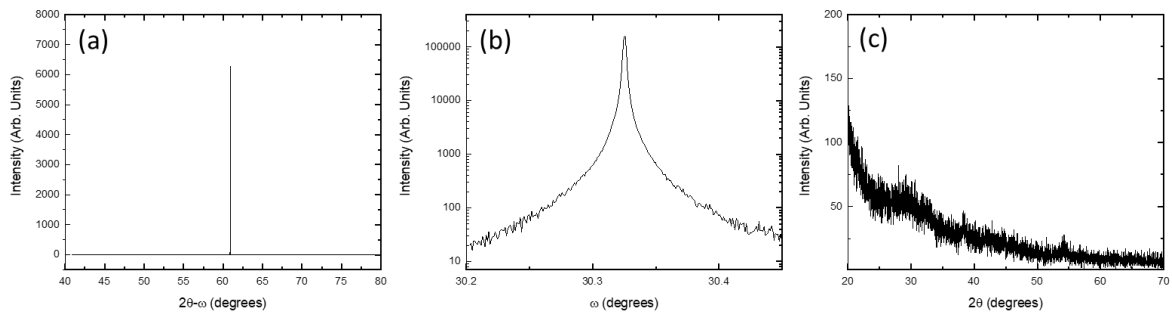


Figure 2. (a) Coupled, (b) omega and (c) 2-theta x-ray diffraction scan of Sn-doped Ga<sub>2</sub>O<sub>3</sub> on (010)-oriented unintentionally doped Ga<sub>2</sub>O<sub>3</sub> substrate.